

Supporting Information

Elimination of Space Charge Effects in Passivation Films: The Key to Substantially Enhancing the Dielectric Properties of Tantalum Oxide Films

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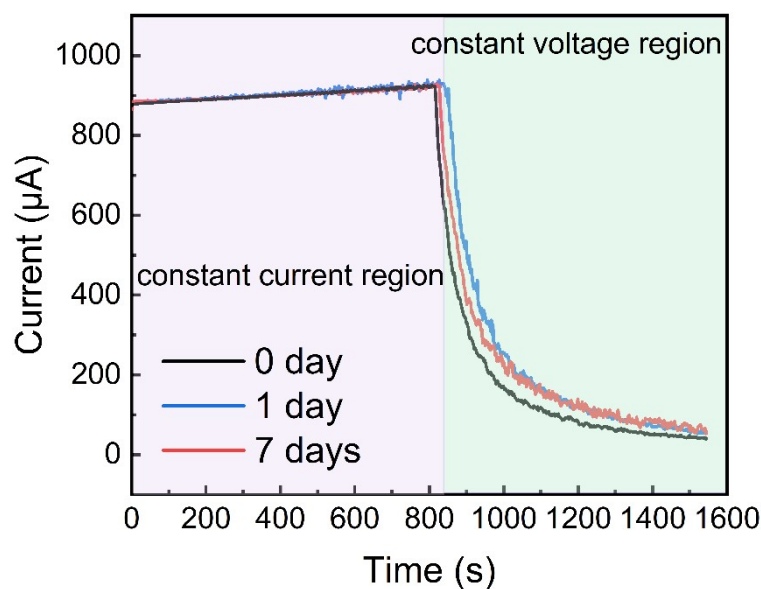


Fig. S1. Current-time curves during the anodic oxidation process for samples with different aging states (unaged, 1-day aged, and 7-day aged).